

## Product Summary

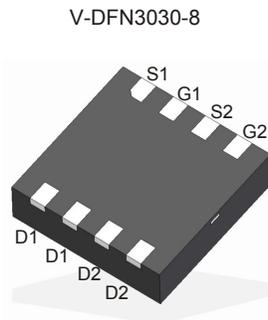
Device	V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> max	I <sub>D</sub> max T <sub>A</sub> = +25°C
Q1	60V	85 mΩ @ V <sub>GS</sub> = 10V	3.1A
		120 mΩ @ V <sub>GS</sub> = 4.5V	2.7A
Q2	-60V	150 mΩ @ V <sub>GS</sub> = -10V	-2.4A
		250 mΩ @ V <sub>GS</sub> = -4.5V	-1.8A

## Description

This new generation MOSFET has been designed to minimize the on-state resistance (R<sub>DS(on)</sub>) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

## Applications

- Power Management Functions
- Analog Switch



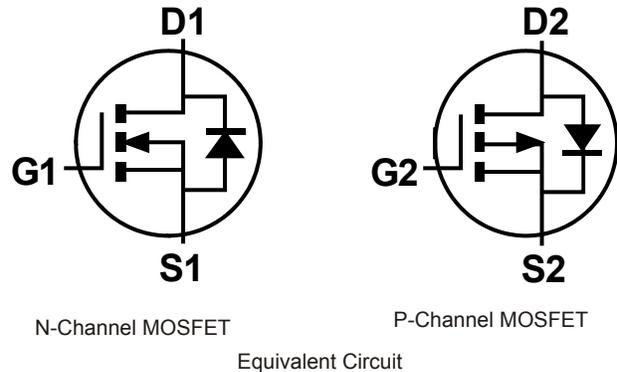
Bottom View

## Features

- Low On-Resistance
- Low Input Capacitance
- Fast Switching Speed
- Low Input/Output Leakage
- Complementary Pair MOSFET
- **Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)**
- **Halogen and Antimony Free. "Green" Device (Note 3)**
- **Qualified to AEC-Q101 Standards for High Reliability**

## Mechanical Data

- Case: V-DFN3030-8
- Case Material: Molded Plastic, "Green" Molding Compound.
- UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram
- Weight: 0.02 grams (approximate)

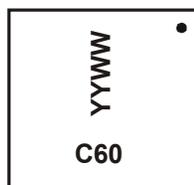


## Ordering Information (Note 4)

Part Number	Case	Packaging
DMC6070LFDH-7	V-DFN3030-8	3,000/Tape & Reel

- Notes:
1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.
  2. See [http://www.diodes.com/quality/lead\\_free.html](http://www.diodes.com/quality/lead_free.html) for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
  3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
  4. For packaging details, go to our website at <http://www.diodes.com/products/packages.html>.

## Marking Information



C60 = Product Type Marking Code  
 YYWW = Date Code Marking  
 YY = Last Digit of Year (ex: 12 for 2012)  
 WW = Week Code (01 ~ 53)

**Maximum Ratings Q1 N-CHANNEL** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic			Symbol	Value	Units
Drain-Source Voltage			V <sub>DSS</sub>	60	V
Gate-Source Voltage			V <sub>GSS</sub>	±20	V
Continuous Drain Current (Note 5) V <sub>GS</sub> = 10V	Steady State	T <sub>A</sub> = +25°C T <sub>A</sub> = +70°C	I <sub>D</sub>	3.1 2.5	A
	t < 10s	T <sub>A</sub> = +25°C T <sub>A</sub> = +70°C	I <sub>D</sub>	3.9 3.1	A
Maximum Body Diode Forward Current (Note 5)			I <sub>S</sub>	2	A
Pulsed Drain Current (10µs pulse, Duty cycle = 1%)			I <sub>DM</sub>	15	A

**Maximum Ratings Q2 P-CHANNEL** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic			Symbol	Value	Units
Drain-Source Voltage			V <sub>DSS</sub>	-60	V
Gate-Source Voltage			V <sub>GSS</sub>	±20	V
Continuous Drain Current (Note 5) V <sub>GS</sub> = -10V	Steady State	T <sub>A</sub> = +25°C T <sub>A</sub> = +70°C	I <sub>D</sub>	-2.4 -1.9	A
	t < 10s	T <sub>A</sub> = +25°C T <sub>A</sub> = +70°C	I <sub>D</sub>	-2.9 -2.3	A
Maximum Body Diode Forward Current (Note 5)			I <sub>S</sub>	-2	A
Pulsed Drain Current (10µs pulse, Duty cycle = 1%)			I <sub>DM</sub>	-12	A

**Thermal Characteristics** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic		Symbol	Value	Units
Total Power Dissipation (Note 5)		P <sub>D</sub>	1.4	W
Thermal Resistance, Junction to Ambient (Note 5)	Steady state	R <sub>θJA</sub>	91	°C/W
	t < 10s		60	
Thermal Resistance, Junction to Case (Note 5)		R <sub>θJC</sub>	32	
Operating and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C

Note: 5. Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate

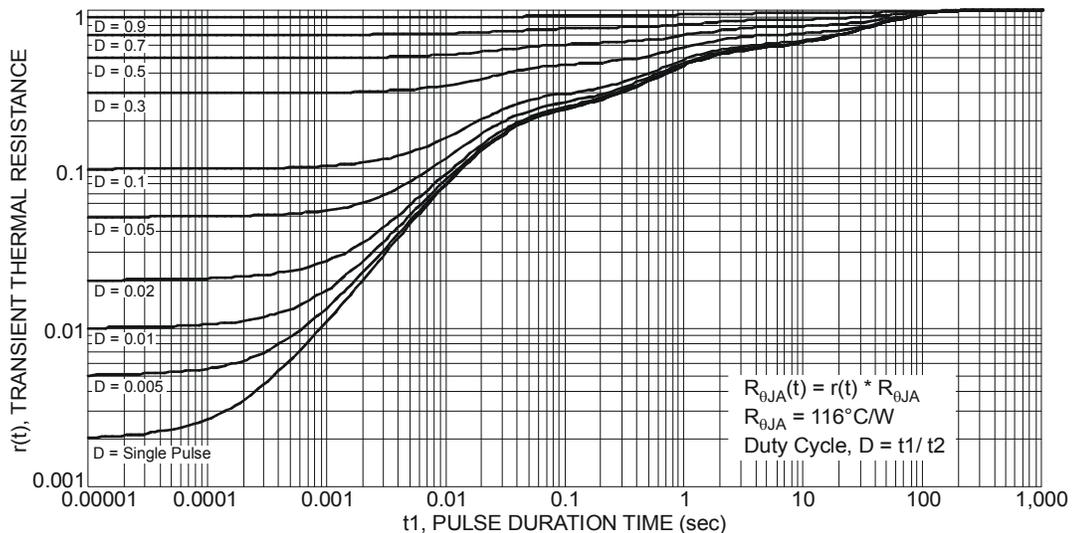
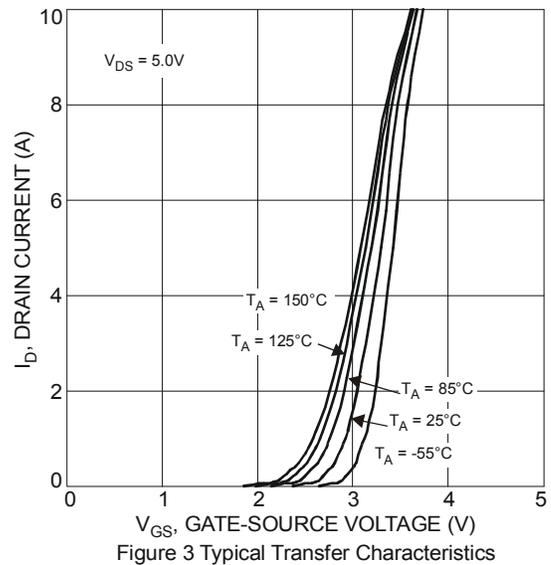
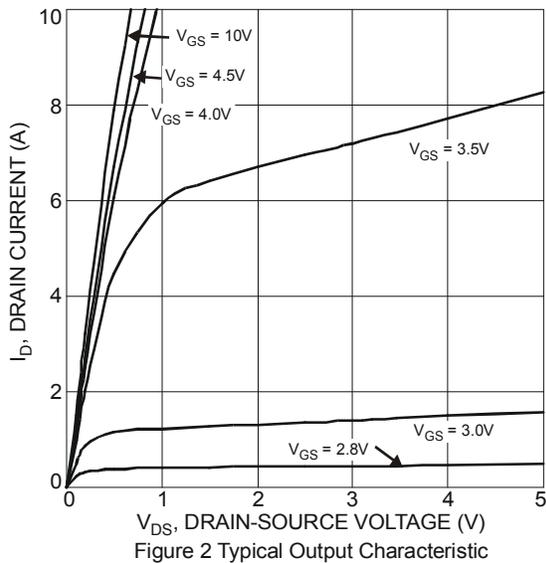


Figure 1 Transient Thermal Resistance

**Electrical Characteristics N-CHANNEL – Q1** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS (Note 6)</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	60	–	–	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
Zero Gate Voltage Drain Current T <sub>J</sub> = +25°C	I <sub>DSS</sub>	–	–	1	μA	V <sub>DS</sub> = 60V, V <sub>GS</sub> = 0V
Gate-Source Leakage	I <sub>GSS</sub>	–	–	±100	nA	V <sub>GS</sub> = ±16V, V <sub>DS</sub> = 0V
<b>ON CHARACTERISTICS (Note 6)</b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	1	–	3	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	–	60	85	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 1.5A
			72	120		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 0.5A
Forward Transfer Admittance	Y <sub>fs</sub>	–	3.7	–	S	V <sub>DS</sub> = 5V, I <sub>D</sub> = 1.5A
Diode Forward Voltage	V <sub>SD</sub>	–	0.7	1.2	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = 3A
<b>DYNAMIC CHARACTERISTICS (Note 7)</b>						
Input Capacitance	C <sub>iSS</sub>	–	731	–	pF	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V, f = 1MHz
Output Capacitance	C <sub>oSS</sub>	–	34	–	pF	
Reverse Transfer Capacitance	C <sub>rSS</sub>	–	23	–	pF	
Gate Resistance	R <sub>g</sub>	–	1.3	–	Ω	V <sub>DS</sub> = 0V, V <sub>GS</sub> = 0V, f = 1MHz
Total Gate Charge (V <sub>GS</sub> = 10V)	Q <sub>g</sub>	–	11.5	–	nC	V <sub>DS</sub> = 30V, I <sub>D</sub> = 3A
Total Gate Charge (V <sub>GS</sub> = 4.5V)	Q <sub>g</sub>	–	5.2	–	nC	
Gate-Source Charge	Q <sub>gs</sub>	–	2.1	–	nC	
Gate-Drain Charge	Q <sub>gd</sub>	–	1.5	–	nC	
Turn-On Delay Time	t <sub>D(on)</sub>	–	9.6	–	ns	V <sub>GS</sub> = 10V, V <sub>DS</sub> = 30V, R <sub>G</sub> = 50Ω, R <sub>L</sub> = 20V
Turn-On Rise Time	t <sub>r</sub>	–	11	–	ns	
Turn-Off Delay Time	t <sub>D(off)</sub>	–	61	–	ns	
Turn-Off Fall Time	t <sub>f</sub>	–	21	–	ns	

Notes: 6. Short duration pulse test used to minimize self-heating effect  
7. Guaranteed by design. Not subject to production testing



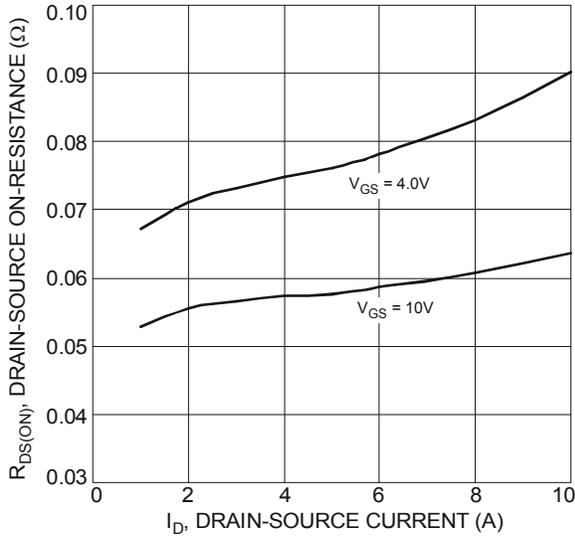


Figure 4 Typical On-Resistance vs. Drain Current and Gate Voltage

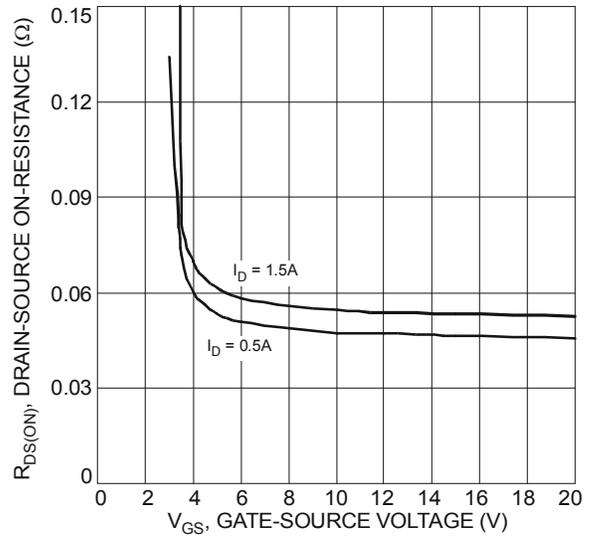


Figure 5 Typical Drain-Source On-Resistance vs. Gate-Source Voltage

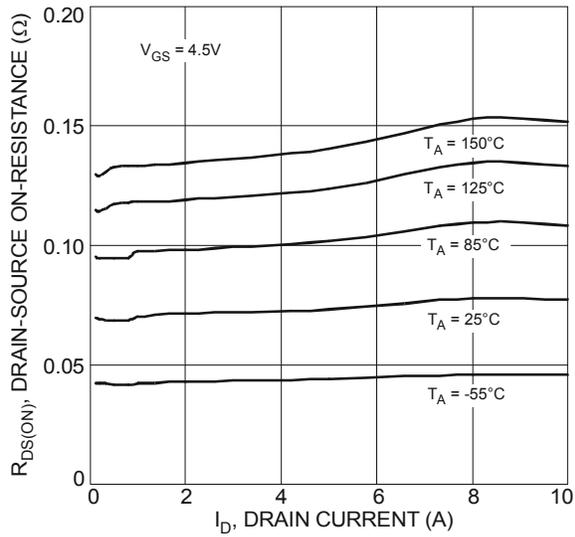


Figure 6 Typical On-Resistance vs. Drain Current and Temperature

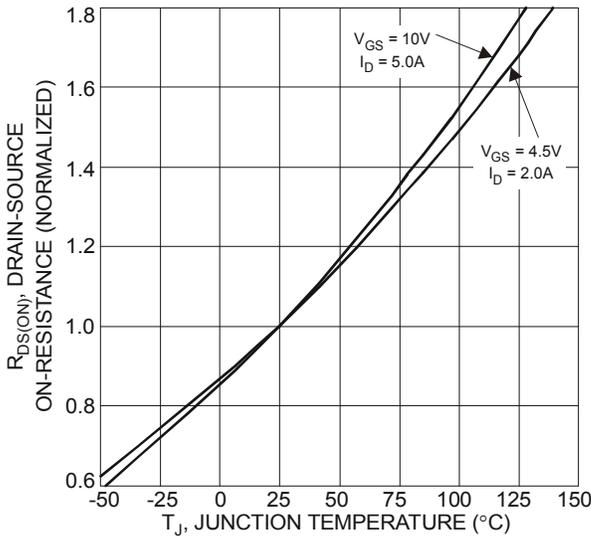


Figure 7 On-Resistance Variation with Temperature

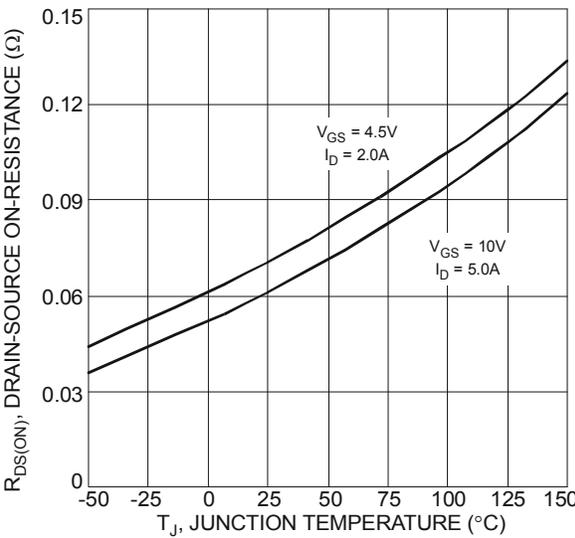


Figure 8 On-Resistance Variation with Temperature

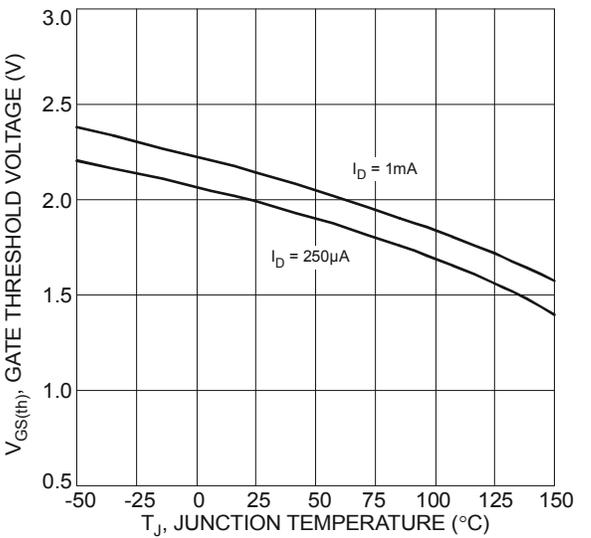


Figure 9 Gate Threshold Variation vs. Ambient Temperature

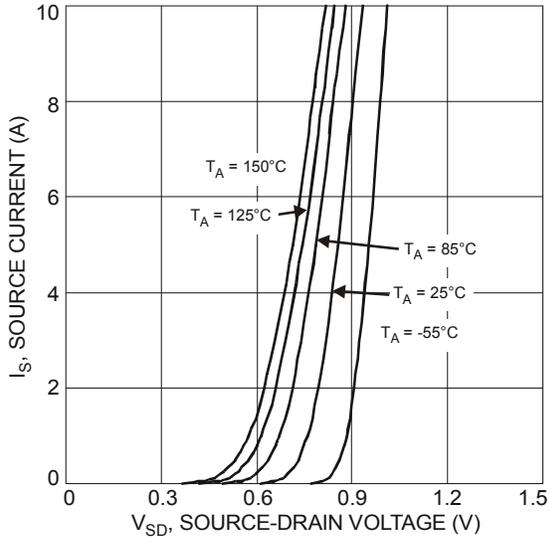


Figure 10 Diode Forward Voltage vs. Current

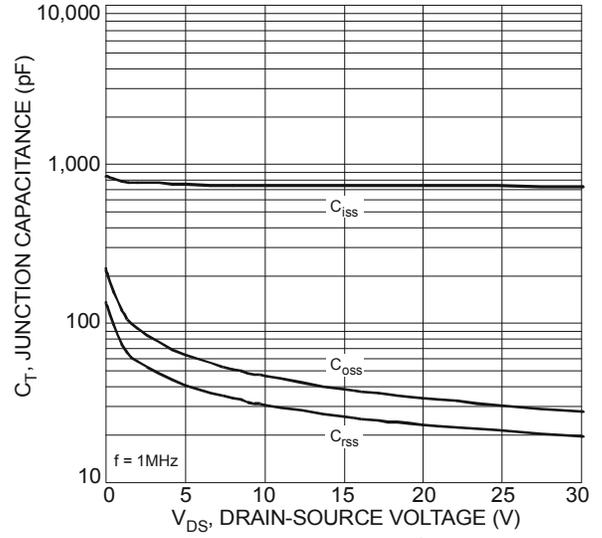


Figure 11 Typical Junction Capacitance

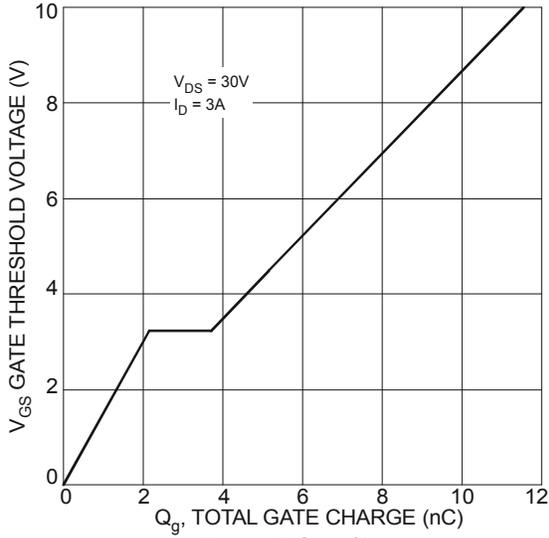
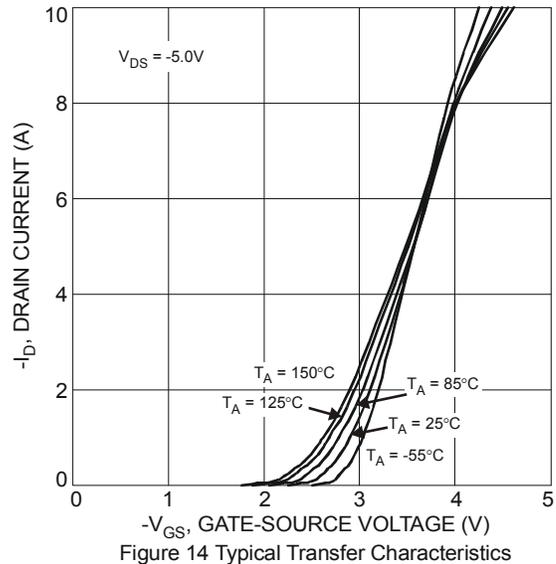
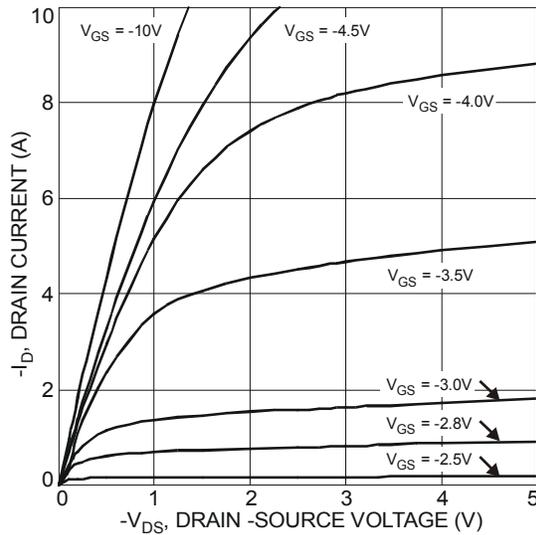


Figure 12 Gate Charge

**Electrical Characteristics P-CHANNEL – Q2 (@T<sub>A</sub> = +25°C, unless otherwise specified.)**

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS (Note 8)</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-60	–	–	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA
Zero Gate Voltage Drain Current T <sub>J</sub> = +25°C	I <sub>DSS</sub>	–	–	-1	μA	V <sub>DS</sub> = -60V, V <sub>GS</sub> = 0V
Gate-Source Leakage	I <sub>GSS</sub>	–	–	±100	nA	V <sub>GS</sub> = ±16V, V <sub>DS</sub> = 0V
<b>ON CHARACTERISTICS (Note 8)</b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	-1	–	-3	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA
Static Drain-Source On-Resistance	R <sub>DS(on)</sub>	–	115	150	mΩ	V <sub>GS</sub> = -10V, I <sub>D</sub> = -1A
			170	250		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -0.5A
Forward Transfer Admittance	Y <sub>fs</sub>	–	2.8	–	S	V <sub>DS</sub> = -5V, I <sub>D</sub> = -1A
Diode Forward Voltage	V <sub>SD</sub>	–	-0.7	-1.2	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = -2A
<b>DYNAMIC CHARACTERISTICS (Note 9)</b>						
Input Capacitance	C <sub>iss</sub>	–	612	–	pF	V <sub>DS</sub> = -20V, V <sub>GS</sub> = 0V, f = 1MHz
Output Capacitance	C <sub>oss</sub>	–	36	–	pF	
Reverse Transfer Capacitance	C <sub>rss</sub>	–	26	–	pF	
Gate Resistance	R <sub>g</sub>	–	13	–	Ω	V <sub>DS</sub> = 0V, V <sub>GS</sub> = 0V, f = 1MHz
Total Gate Charge (V <sub>GS</sub> = -10V)	Q <sub>g</sub>	–	8.9	–	nC	V <sub>DS</sub> = -30V, I <sub>D</sub> = -2A
Total Gate Charge (V <sub>GS</sub> = -4.5V)	Q <sub>g</sub>	–	4.3	–	nC	
Gate-Source Charge	Q <sub>gs</sub>	–	1.4	–	nC	
Gate-Drain Charge	Q <sub>gd</sub>	–	1.7	–	nC	
Turn-On Delay Time	t <sub>D(on)</sub>	–	7.6	–	ns	V <sub>GS</sub> = -10V, V <sub>DS</sub> = -30V, R <sub>G</sub> = 50Ω, I <sub>D</sub> = -1A
Turn-On Rise Time	t <sub>r</sub>	–	11.6	–	ns	
Turn-Off Delay Time	t <sub>D(off)</sub>	–	79.8	–	ns	
Turn-Off Fall Time	t <sub>f</sub>	–	37.8	–	ns	

Notes: 8. Short duration pulse test used to minimize self-heating effect  
 9. Guaranteed by design. Not subject to production testing



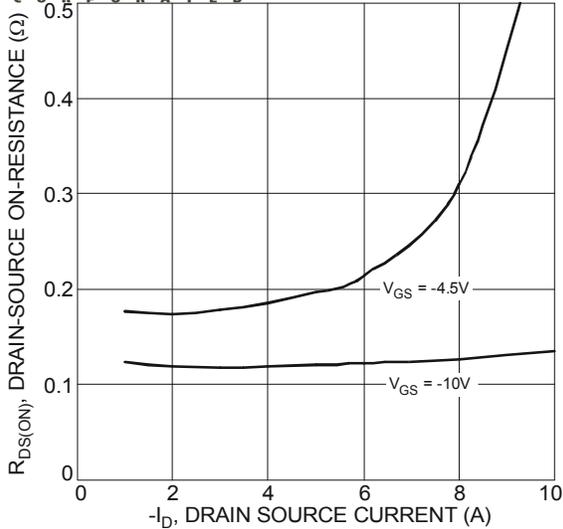


Figure 15 Typical On-Resistance vs. Drain Current and Gate Voltage

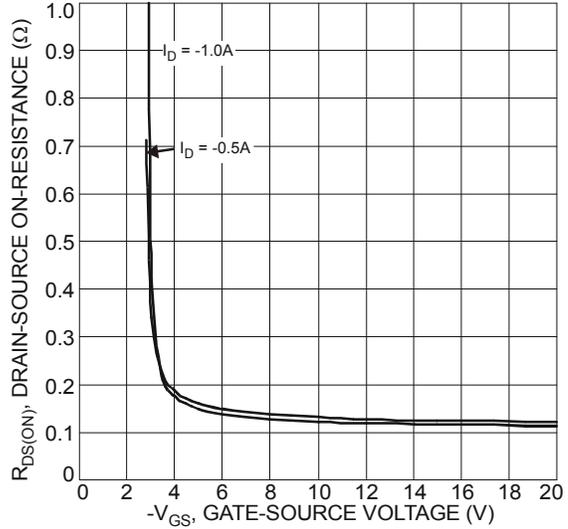


Figure 16 Typical Drain-Source On-Resistance vs. Gate-Source Voltage

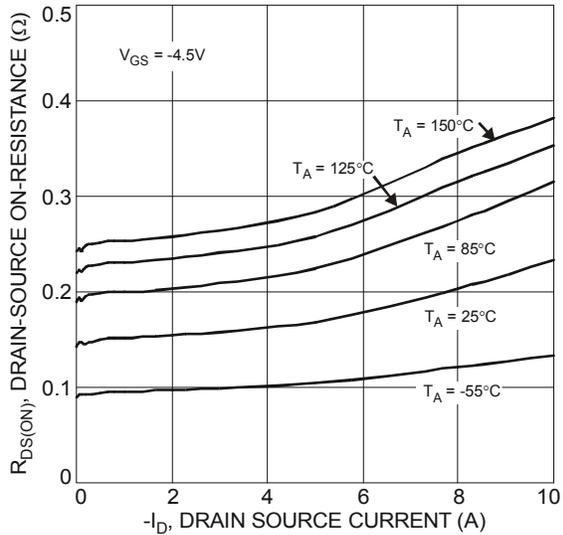


Figure 17 Typical On-Resistance vs. Drain Current and Temperature

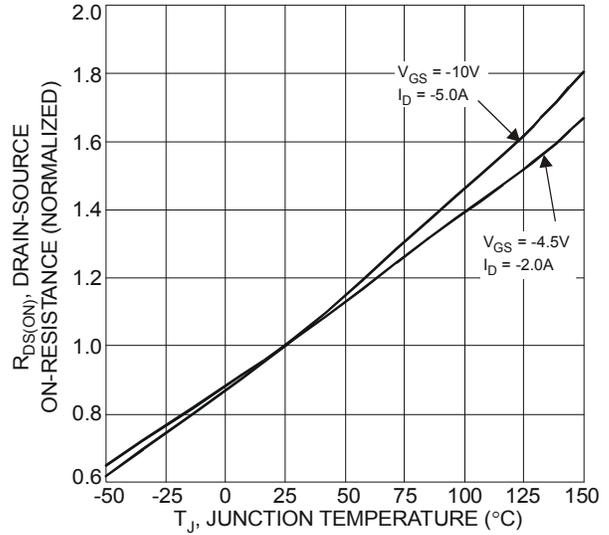


Figure 18 On-Resistance Variation with Temperature

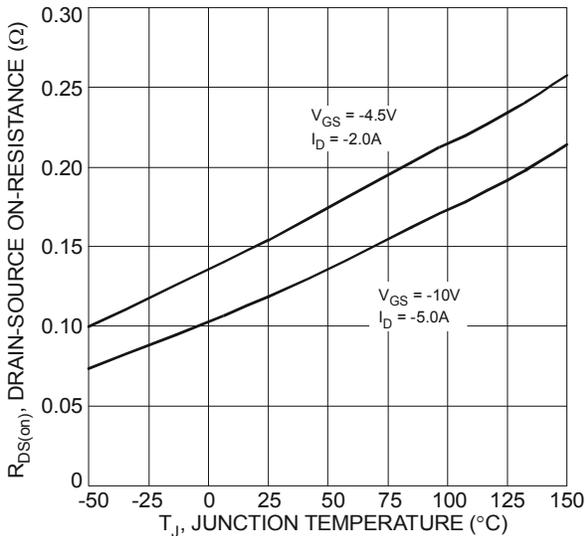


Figure 19 On-Resistance Variation with Temperature

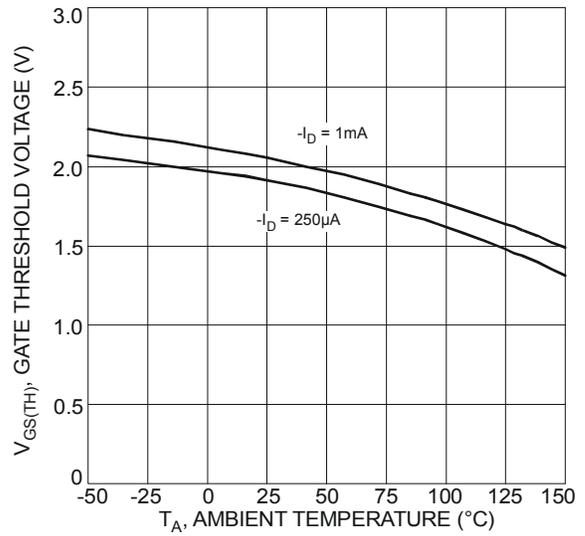
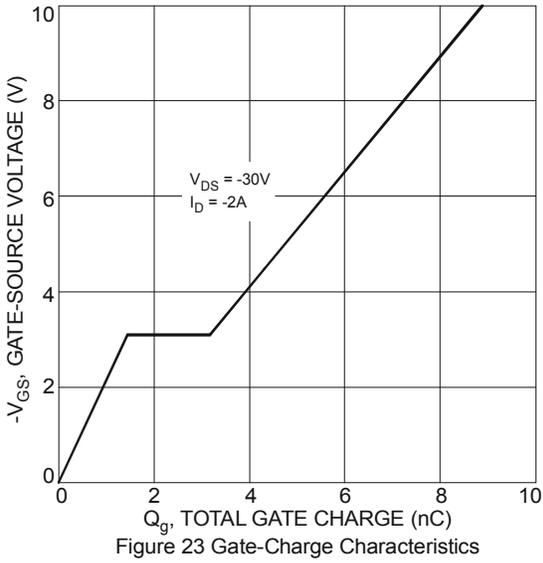
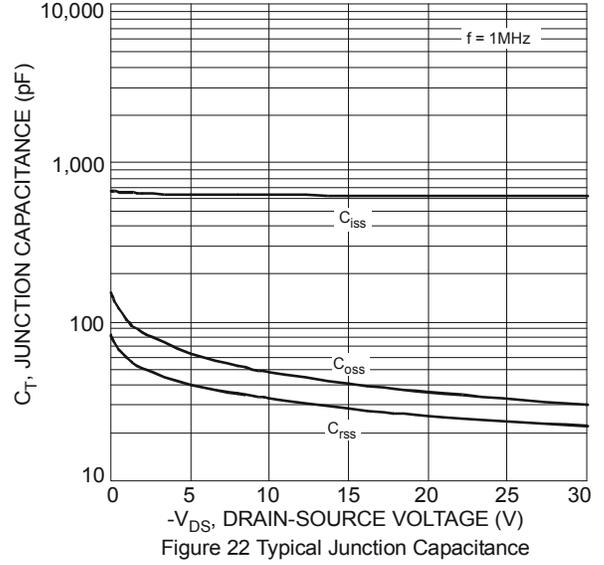
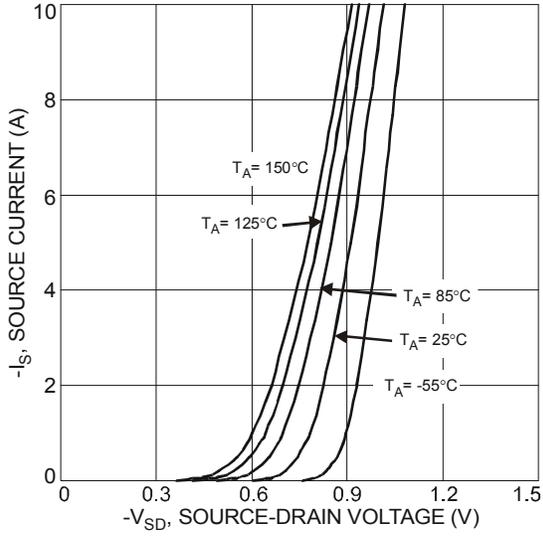
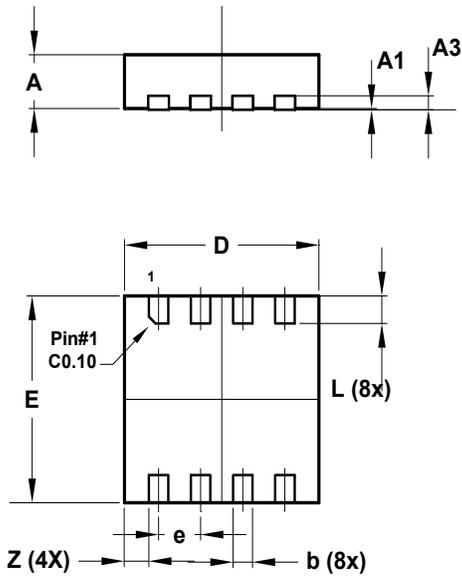


Figure 20 Gate Threshold Variation vs. Ambient Temperature



**Package Outline Dimensions**

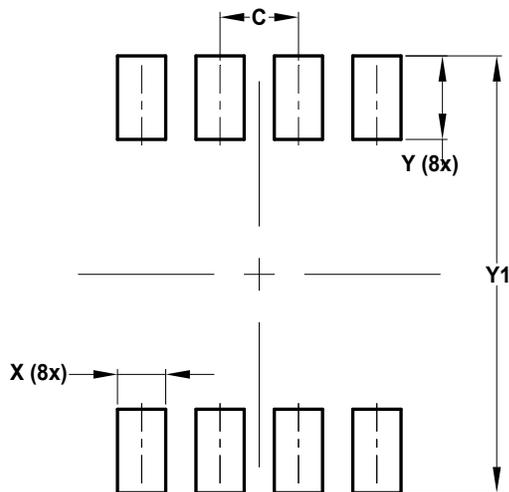
Please see AP02002 at <http://www.diodes.com/datasheets/ap02002.pdf> for latest version.



V-DFN3030-8			
Dim	Min	Max	Typ
A	0.75	0.85	0.80
A1	0	0.05	0.02
A3	-	-	0.203
b	0.25	0.35	0.30
D	2.95	3.05	3.00
E	2.95	3.05	3.00
e	-	-	0.65
L	0.55	0.65	0.60
Z	-	-	0.375
All Dimensions in mm			

**Suggested Pad Layout**

Please see AP02001 at <http://www.diodes.com/datasheets/ap02001.pdf> for the latest version.



Dimensions	Value (in mm)
C	0.650
X	0.400
Y	0.850
Y1	3.400

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